

Richard Wilkins

List of Publications by Year in descending order

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Version: 2024-02-01

14
papers

238
citations

1307594

7
h-index

1199594

12
g-index

14
all docs

14
docs citations

14
times ranked

203
citing authors

#	ARTICLE	IF	CITATIONS
1	Single Event Effects in Si and SiC Power MOSFETs Due to Terrestrial Neutrons. IEEE Transactions on Nuclear Science, 2017, 64, 529-535.	2.0	73
2	Terrestrial Neutron-Induced Failures in Silicon Carbide Power MOSFETs and Diodes. IEEE Transactions on Nuclear Science, 2018, 65, 1248-1254.	2.0	39
3	Cosmic radiation dose measurements from the RaD-X flight campaign. Space Weather, 2016, 14, 874-898.	3.7	30
4	Predicting Cosmic Ray-Induced Failures in Silicon Carbide Power Devices. IEEE Transactions on Nuclear Science, 2019, 66, 1828-1832.	2.0	21
5	Enabling Scatterometry as an In-Line Measurement Technique for 32 nm BEOL Application. IEEE Transactions on Semiconductor Manufacturing, 2011, 24, 499-512.	1.7	14
6	Terrestrial Neutron Induced Failure in Silicon Carbide Power MOSFETs. , 2014, , .		13
7	Total Ionizing Dose X-ray Radiation Effects on MWCNT/PMMA Thin Film Composites. IEEE Nanotechnology Magazine, 2015, 14, 152-158.	2.0	13
8	Micronuclei induction in human fibroblasts exposed in vitro to Los Alamos high-energy neutrons. Advances in Space Research, 2007, 40, 1754-1757.	2.6	12
9	Space and Terrestrial Radiation Response of Silicon Carbide Power MOSFETs. , 2017, , .		12
10	X-ray radiation effects on thin film nanocomposites of functionalized and copper coated multi-walled carbon nanotube and poly(methyl methacrylate). Surfaces and Interfaces, 2019, 17, 100362.	3.0	3
11	X-ray Radiation Effects on SWCNT/PMMA Thin Film Nanocomposites. IEEE Nanotechnology Magazine, 2021, 20, 517-524.	2.0	3
12	Beamline and Flight Comparisons of the ARMAS Flight Module With the Tissue Equivalent Proportional Counter for Improving Atmospheric Radiation Monitoring Accuracy. Space Weather, 2020, 18, e2020SW002599.	3.7	2
13	Energy Dependence of Atmospheric Neutron-Induced Failures in Silicon Carbide Power Devices. IEEE Transactions on Nuclear Science, 2022, 69, 900-907.	2.0	2
14	Variability Modeling and Process Optimization for the 32 nm BEOL Using In-Line Scatterometry Data. IEEE Transactions on Semiconductor Manufacturing, 2014, 27, 260-268.	1.7	1